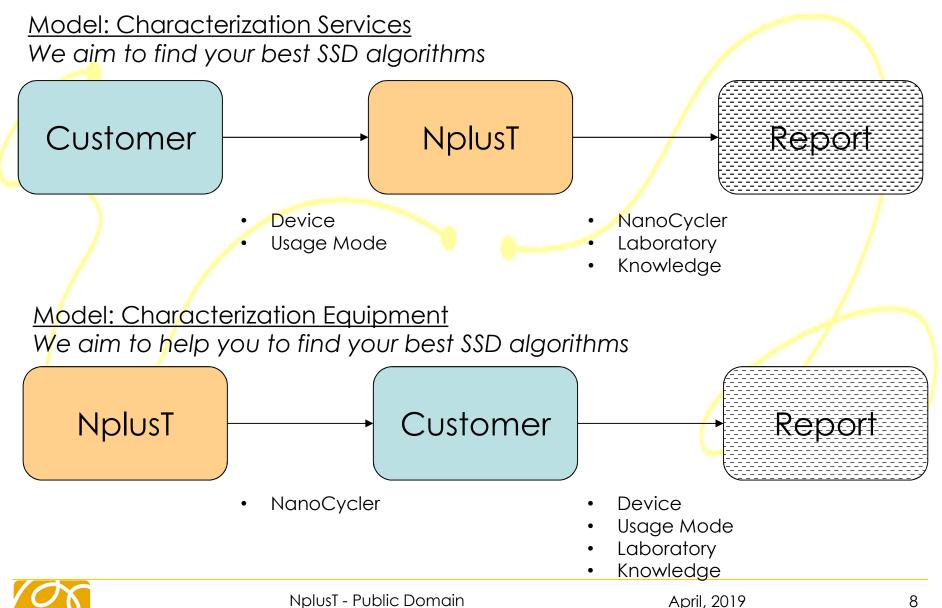
NAND Characterization

We aim to find your best SSD algorithms We aim to help you to find your best SSD algorithms

Partnering with NplusT



Why NAND Characterization ??

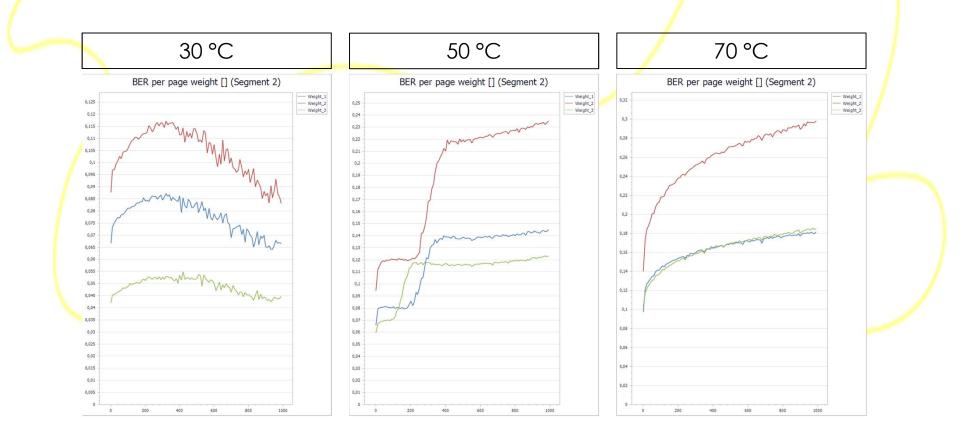




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Discovering the NAND

How does the RBER change after programming ? Does it depend also on the temperature ?





Limited Set of Information

Datasheets cover AC/DC/Functional parameters but there are very few details about how to reach the specified reliability

Multiple uncovered topics:

- Ex.: read-retry. Which option should I pick? I test dozens of options but QoS looks horrible !
- o Ex.: Do program and erase suspend operations impact raw BER ?
- o Ex.: How many read operations can run on a block between two erase cycles ?

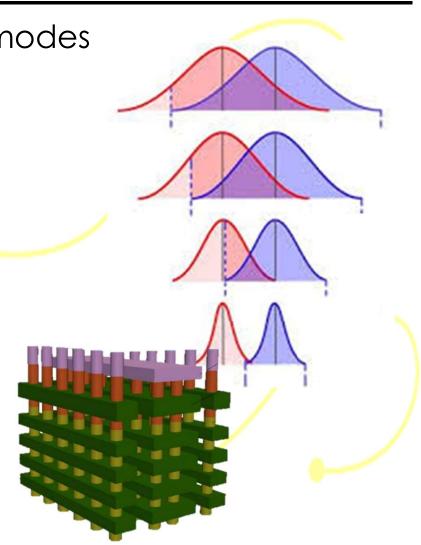
0 ...



Flash Memories Are Imperfect

NANDs have inherent failure modes

- Read Errors
- o Cell Interference
- o Read Disturb Effects
- NANDs wear out during life
 - o Limited Endurance (P/E Cycles)
 - 🔶 Retention Time
 - Number of Read Operations
- Limits strongly depend on
 - o Technology
 - SLC/MLC/TLC/QLC
 - 2D/3D
 - o <u>Usage Mode !</u>





Compensation Algorithms Needed

Error Correction
Read Retry
Bad Block Management
Wear Levelling

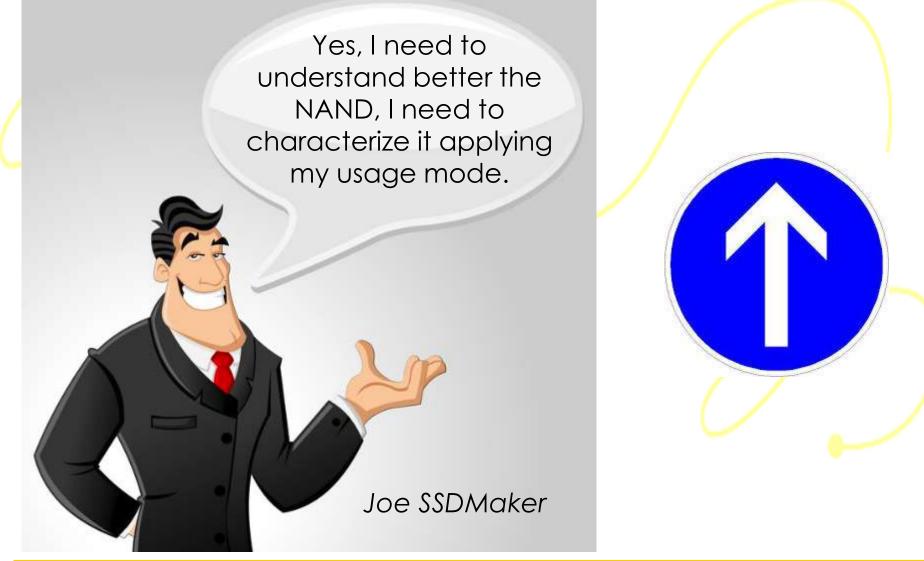


What to compensate ? And how ??



Adjust

I Need NAND Characterization !!

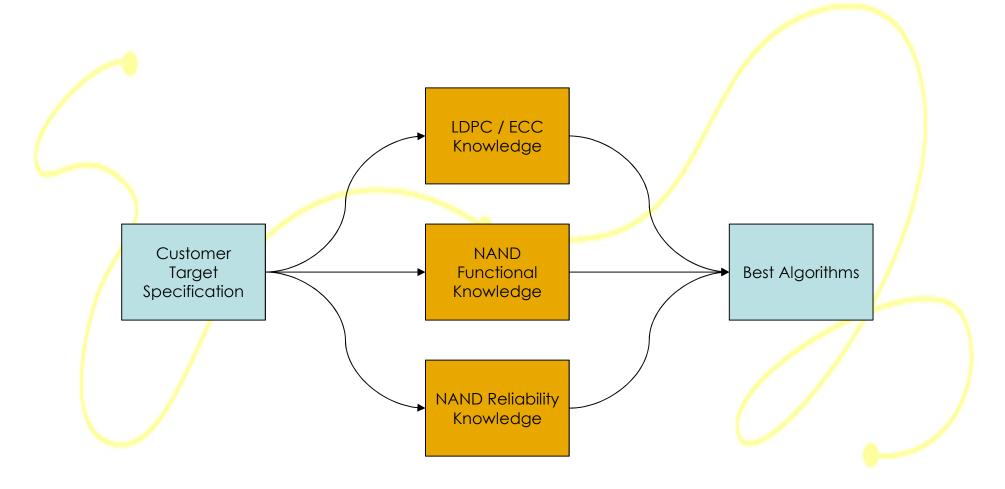




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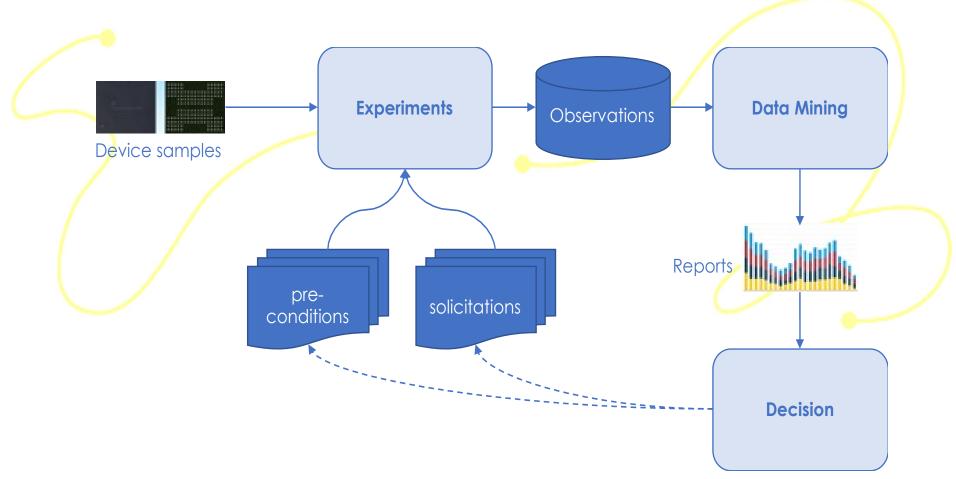


Context of NAND Characterization





Fully Integrated <u>SSD-NAND Characterization Flow</u>





Characterization Capabilities

- Environment and operational parameters
- Reliability conditions
- Read Retry options
- LDPC and Soft Decoding
- □ <u>Suspend operations → SSD QoS</u>
- Algorithms for NAND lifetime extension
- Miscellaneous

